

10/508834

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*[Signature]*

PATENT

Docket No.: 4590-337

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :  
Emmanuel DE CHAMBOST et al. : Confirmation No.  
U.S. Patent Application No. *not yet assigned* :  
Filed: *herewith* :

For: DEVICE FOR MEASURING THE EMISSION OF X RAYS PRODUCED BY AN OBJECT  
EXPOSED TO AN ELECTRON BEAM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above-identified application and readily available to the Examiner. Therefore it is believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. A copy of the foreign search report is attached for the Examiner's information. Acknowledgement and consideration of these documents are respectfully requested.

Respectfully submitted,

LOWE HAUPTMAN GILMAN & BERNER, LLP

*Kenneth M. Berner*

Kenneth M. Berner  
Registration No. 37,093

1700 Diagonal Road, Suite 310  
Alexandria, Virginia 22314  
(703) 684-1111 KMB/eb  
Facsimile: (703) 518-5499  
Date: September 23, 2004

**INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION**

(PTO-1449)

ATTY. DOCKET NO.  
**4590-337**

**U.S. APPLICATION NO.**  
**Not yet assigned**

**APPLICANT**  
Emmanuel DE CHAMBOST et al.

FILING DATE <b>herewith</b>	GROUP
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## **U.S. PATENT DOCUMENTS**

## **FOREIGN PATENT DOCUMENTS**

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	<b>01 95365 A</b>	<b>12/13/2001</b>	<b>WO</b>				

**OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)**


**EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and provide initial below. Cite by reference to application number, page, line and column.